

RENESAS TECHNICAL UPDATE

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Product Category	MPU/MCU		Document No.	TN-RA*-A0075A/E	Rev.	1.00
Title	Addition to the Electrical Characteristics for the IIC of the RA6T2 Group MCU Products		Information Category	Technical Notification		
Applicable Product	RA6T2 Group	Lot No.	Reference Document	RA6T2 Group User's Manual : Hardware Rev.1.30		
		All				

This document describes addition of specifications for the electrical characteristics of the IIC in the RA6T2 Group User's Manual: Hardware, Rev.1.30.

The characteristics of SCL output minimum high/low pulse widths and START condition input hold time are added to Table 46.32, IIC Timing (2) as follows. Some terms are also corrected.

Before correction

Table 46.32 IIC Timing (2)

Setting of the SCL0_A, SDA0_A pins are not required with the Port Drive Capability bit in the PmnPFS register.

Parameter		Symbol	Min.	Max.	Unit	Test Conditions	
IIC (Hs-mode) BFCTL.HSME = 1	SCL input cycle time	t_{SCL}	$10(12) \times t_{IICcyc} + 80$	—	ns	Figure 46.48	
	SCL input high pulse width	t_{SCLH}	$5(6) \times t_{IICcyc}$	—	ns		
	SCL input low pulse width	t_{SCLL}	$5(6) \times t_{IICcyc}$	—	ns		
	SCL rise time	$C_b = 400pF$	t_{SrCL}	—	80		ns
		$C_b = 100pF$		—	40		
	SDA rise time	$C_b = 400pF$	t_{SrDA}	—	160		ns
		$C_b = 100pF$		—	80		
	SCL fall time	$C_b = 400pF$	t_{SiCL}	—	80		ns
		$C_b = 100pF$		—	40		
	SDA fall time	$C_b = 400pF$	t_{SiDA}	—	160		ns
		$C_b = 100pF$		—	80		
	SCL, SDA input spike pulse removal time		t_{SP}	0	$1(1) \times t_{IICcyc}$		ns
	Repeated START condition input setup time		t_{STAS}	40	—		ns
	STOP condition input setup time		t_{STOS}	40	—		ns
	Data input setup time		t_{SDAS}	10	—		ns
Data input hold time	$C_b = 400pF$	t_{SDAH}	0	150	ns		
	$C_b = 100pF$		0	70			
SCL, SDA capacitive load		C_b^{*1}	—	400	pF		

After correction

Table 46.32 IIC Timing (2)

Setting of the SCL0_A, SDA0_A pins are not required with the Port Drive Capability bit in the PmnPFS register.

Parameter			Symbol	Min.	Typ.	Max.	Unit	Test Conditions
IIC (Hs-mode) BFCTL.HSME = 1	SCL input cycle time		t _{SCL}	10(12) × t _{IICcyc} + 80	—	—	ns	Figure 46.48
	SCL input high pulse width		t _{SCLH}	5(6) × t _{IICcyc}	—	—	ns	
	SCL input low pulse width		t _{SCLL}	5(6) × t _{IICcyc}	—	—	ns	
	SCL rise time	C _b = 400pF	t _{SrCL}	—	—	80	ns	
		C _b = 100pF		—	—	40		
	SDA rise time	C _b = 400pF	t _{SrDA}	—	—	160	ns	
		C _b = 100pF		—	—	80		
	SCL fall time	C _b = 400pF	t _{SiCL}	—	—	80	ns	
		C _b = 100pF		—	—	40		
	SDA fall time	C _b = 400pF	t _{SiDA}	—	—	160	ns	
		C _b = 100pF		—	—	80		
	SCL, SDA input spike pulse removal time		t _{SP}	0	—	1(1) × t _{IICcyc}	ns	
	START condition input hold time		t _{STAH}	t _{IICcyc} + 40	—	—	ns	
	Repeated START condition input setup time		t _{STAS}	40	—	—	ns	
	STOP condition input setup time		t _{STOS}	40	—	—	ns	
	Data input setup time		t _{SDAS}	10	—	—	ns	
	Data input hold time	C _b = 400pF	t _{SDAH}	0	—	150	ns	
		C _b = 100pF		0	—	70		
SCL, SDA capacitive load		C _b ^{*1}	—	—	400	pF		
SCL output minimum high pulse width	C _b = 400pF	t _{SCLH}	—	120	225	ns		
	C _b = 100pF		—	60	130			
SCL output minimum low pulse width	C _b = 400pF	t _{SCLL}	—	—	320	ns		
	C _b = 100pF		—	—	160			